

XA-9947
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Nobuyuki SUGII et al.

Appln. No.:

Filed: Herewith

For: INSULATED-GATE FIELD-EFFECT TRANSISTOR, METHOD OF
FABRICATING SAME, AND SEMICONDUCTOR DEVICE EMPLOYING
THE SAME

* * *

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. § 1.56, and without any
assertion as to materiality or prior art effect, the
documents listed on the attached Form PTO-1449 are hereby
cited.

The Japanese documents AJ-AM on the attached List are
accompanied by English abstracts. Documents AJ-AL are also
cited in the specification, on pages 2-5.

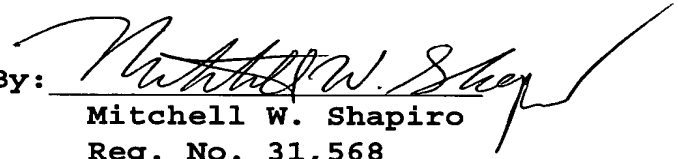
Documents AP and AQ are cited in the specification, on
pages 2-4, and their relevance is indicated therein.

Respectfully submitted,

MWS:sjk

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By:


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September 30, 2003

FORM PTO-1449				Atty. Docket No. XA-9947		Appln. No.	
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>				Applicant Nobuyuki SUGII et al.			
				Filing Date HEREWITH		Group	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA	6,563,152	05/13/03	Roberds et al.	257	288	
	AB	6,475,869	11/05/02	Yu	438	303	
	AC	6,403,981	06/11/02	Yu	257	63	
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AJ	2002-16255	01/18/02	Japan			Abstract
	AK	9-321307	12/12/97	Japan			Abstract
	AL	2000-286418	10/13/00	Japan			Abstract
	AM	2003-17710	01/17/03	Japan			Abstract
	AN						
	AO						
OTHER (including author, title, date, pertinent pages, etc.)							
	AP	Hisamoto et al., "A Folded-channel MOSFET for Deep-sub-tenth Micron Era," Proceedings of the International Electronic Device Conference (IEDM), 1988, pp. 1032-1034.					
	AQ	Nikkei Electronics, July 16, 2001, pp. 63-70.					
	AR						
Examiner				Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							